		1,00							
Form PTO 1449	U.S. DEPARTMENT OF COMMERCE PATENT, AND TRADEMARK OFFICE			ATTY DOCKET NO.			SERIAL NO.		
II <b>X.&gt;</b> ~				252092US6			10/827,336		
		Caren		APPLICANT					
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Shouji TSUCHIYA, et al.					
				FILING DATE			GROUP		
				April 20, 2004			2873		
U.S. PATENT DOCUMENTS									
EXAMINER		DOCUMENT	DATE		NAME	CLASS	SUB	F	ILING DATE
INITIAL		NUMBER	DATE		NAIWE CLASS		CLASS IF APPROPRIATE		
	AA								
	AB								
	AC								/
	AD								
	AE			<u> </u>					
	AF								
	AG								
	AH	/							
	Al								
	AJ		Î						
	AK								_
	AL	- <del>- 2</del>		i					
	AM				/	· · · · ·			
	AN				<del></del>	1			
			FO	REIGN PATEN	T DOCUMENTS	<u>.</u> L			
FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE		COUNTRY			TRANS	LATION NO
RU	AO	0 811 874	12/10/1997	EUROPE					
	AP								_
	AQ								
	AR								
	AS								
	AT								
	AU		-						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
A.,	AV	Patent Abstracts of Japan, JP 2000-330179, November 30, 2000							
	AV Patent Abstracts of Japan, JP 2001-051332, February 23, 2001								
bu									
A Patent Abstracts of Japan, JP 07-092537, April 7, 1995									
1 /M	AX								
hu	AY	Patent Abstracts of Japan, JP 10-186202, July 14, 1998							
Ry		Patent Abstracts of Ja	6, 2000						
	AZ					Addi Addi	Additional References sheet(s) attached		
Examiner X Mack					······································	Date Considered 2/7/65			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									